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Electrets, 1994. (ISE 8), 8th International Symposium on , 7-9 Sep 1994

Page(s): 916 -921

[\[Abstract\]](#) [\[PDF Full-Text \(312 KB\)\]](#) **IEEE CNF****2 Application of a rheological model to the simulation of ferroelectric hysteresis***De Magistris, M.; Miano, G.; Tucci, V.; Visone, C.;*

Electrets, 1994. (ISE 8), 8th International Symposium on , 7-9 Sep 1994

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Jacobs, J.B.; Unnikrishnan, S.; Grider, T.; Thakar, G.V.; Joyner, K.; Eklund, R.H.  
Houston, T.W.;

SOI Conference, 1998. Proceedings., 1998 IEEE International , 5-8 Oct 1998

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[\[Abstract\]](#) [\[PDF Full-Text \(216 KB\)\]](#) **IEEE CNF**

---

**5 Temperature dependent hysteretic propagation delay in FB SOI inver chain**

Duckhyun Chang; Byonug Min; Veeraraghavan, S.; Mendicino, M.; Cooper, T.;  
S.; Cox, K.;

SOI Conference, 1999. Proceedings. 1999 IEEE International , 1999

Page(s): 82 -83

[\[Abstract\]](#) [\[PDF Full-Text \(100 KB\)\]](#) **IEEE CNF**

---

**6 Hysteresis in floating-body PD/SOI CMOS circuits**

Pelella, M.M.; Chuang, C.T.; Tretz, C.; Curran, B.W.; Rosenfield, M.G.;

VLSI Technology, Systems, and Applications, 1999. International Symposium o  
1999

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[\[Abstract\]](#) [\[PDF Full-Text \(308 KB\)\]](#) **IEEE CNF**

---

**7 Partially depleted silicon-on-insulator (SOI): a device design/modelin circuit perspective**

Assaderaghi, F.; Shahidi, G.; Fung, S.; Sherony, M.; Wagner, L.; Sleight, J.; Lo  
Wu, K.; Chen, T.-C.;

Microelectronics, 2000. ICM 2000. Proceedings of the 12th International Confer  
, 2000

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[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) **IEEE CNF**

---

**8 High frequency input isolation circuit for asynchronous CMOS macros PD/SOI technology**

Joshi, R.V.; Hwang, W.; Chuang, C.T.;

SOI Conference, 2000 IEEE International , 2000

Page(s): 140 -141

[\[Abstract\]](#) [\[PDF Full-Text \(116 KB\)\]](#) **IEEE CNF**

---

**9 Analysis and suppression of hysteretic behaviors in PD-SOI CMOS circ**

Higuchi, H.; Ikeda, T.;



[\[Abstract\]](#) [\[PDF Full-Text \(444 KB\)\]](#) **IEEE JNL**

---

**15 A comparative analysis of the dynamic behavior of BTG/SOI MOSFET circuits with distributed body resistance**

*Workman, G.O.; Fossum, J.G.;*

Electron Devices, IEEE Transactions on , Volume: 45 Issue: 10 , Oct 1998

Page(s): 2138 -2145

[\[Abstract\]](#) [\[PDF Full-Text \(304 KB\)\]](#) **IEEE JNL**

---

**16 Total dose induced latch in short channel NMOS/SOI transistors**

*Ferlet-Cavrois, V.; Quoizola, S.; Musseau, O.; Flament, O.; Leray, J.L.; Pelloie, Raynaud, C.; Faynot, O.;*

Nuclear Science, IEEE Transactions on , Volume: 45 Issue: 6 , Dec 1998

Page(s): 2458 -2466

[\[Abstract\]](#) [\[PDF Full-Text \(928 KB\)\]](#) **IEEE JNL**

---

**17 A dynamic-threshold SOI device with a J-FET embedded source struc and a merged body-bias-control transistor. II. Circuit simulation**

*Horiuchi, M.;*

Electron Devices, IEEE Transactions on , Volume: 47 Issue: 8 , Aug 2000

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[\[Abstract\]](#) [\[PDF Full-Text \(152 KB\)\]](#) **IEEE JNL**

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*Sundaresan, R.; Matloubian, M.; Chen, C.-E.; Bailey, W.E.; Mao, B.; Blake, T.G  
Peterson, A.; Pollack, G.P.;*

SOS/SOI Technology Workshop, 1988. Proceedings., 1988 IEEE , 3-5 Oct 1988  
Page(s): 81

[\[Abstract\]](#) [\[PDF Full-Text \(60 KB\)\]](#) **IEEE CNF****2 Gettering of threading dislocations and oxide precipitates in SIMOX m**

*Tomozane, M.; Liaw, H.M.;*

SOS/SOI Technology Conference, 1989., 1989 IEEE , 3-5 Oct 1989  
Page(s): 60 -61

[\[Abstract\]](#) [\[PDF Full-Text \(140 KB\)\]](#) **IEEE CNF****3 Native silicon oxide agglomeration prior to solid-phase epitaxy using thermal processing**

*Leung, D.L.; Knudsen, J.F.; Swanson, D.J.; Hill, B.J.; Mayer, D.C.;*

SOS/SOI Technology Conference, 1990., 1990 IEEE , 2-4 Oct 1990  
Page(s): 57 -58

[\[Abstract\]](#) [\[PDF Full-Text \(148 KB\)\]](#) **IEEE CNF****4 TEM analysis of SIMOX produced by multiple implantation and anneal**

*Seraphin, S.; Cordts, B.F., III;*

SOI Conference, 1991. Proceedings., 1991 IEEE International , 1-3 Oct 1991

Page(s): 86 -87

[\[Abstract\]](#) [\[PDF Full-Text \(208 KB\)\]](#) **IEEE CNF**

---

**5 Characterization of transistors fabricated in solid-phase epitaxially re material**

*Leung, D.L.; Mayer, D.C.;*

SOI Conference, 1991. Proceedings., 1991 IEEE International , 1-3 Oct 1991

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[\[Abstract\]](#) [\[PDF Full-Text \(132 KB\)\]](#) **IEEE CNF**

---

**6 Microstructural changes in oxygen implanted SOI material at interme annealing steps in thermal ramping**

*Park, J.C.; Krause, S.J.; Roitman, P.;*

SOI Conference, 1991. Proceedings., 1991 IEEE International , 1-3 Oct 1991

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[\[Abstract\]](#) [\[PDF Full-Text \(184 KB\)\]](#) **IEEE CNF**

---

**7 A SiGe strain layer for gettering Fe in SIMOX**

*Campisi, G.J.; Thompson, P.; Anc, M.; Cordts, B.; Ioannou, D.E.;*

SOI Conference, 1993. Proceedings., 1993 IEEE International , 5-7 Oct 1993

Page(s): 56 -57

[\[Abstract\]](#) [\[PDF Full-Text \(132 KB\)\]](#) **IEEE CNF**

---

**8 Annealing characteristics of radiation induced leakage in SOS MOSFET**

*Chao, E.Y.; Hu, C.; Wu, S.; Li, G.P.; Liu, P.; White, J.; Kjar, R.;*

SOI Conference, 1993. Proceedings., 1993 IEEE International , 5-7 Oct 1993

Page(s): 84 -85

[\[Abstract\]](#) [\[PDF Full-Text \(112 KB\)\]](#) **IEEE CNF**

---

**9 Integrity of gate oxides formed on SIMOX wafers**

*Brown, G.A.; Hosack, H.H.; Joyner, K.; Krull, W.A.;*

SOI Conference, 1994 Proceedings., 1994 IEEE International , 3-6 Oct 1994

Page(s): 73 -74

[\[Abstract\]](#) [\[PDF Full-Text \(156 KB\)\]](#) **IEEE CNF**

---

**10 Single pulse output of partially depleted SOI FETs**

Jenkins, K.A.; Taur, Y.; Sun, J.Y.-C.;

SOI Conference, 1996. Proceedings., 1996 IEEE International , 30 Sep-3 Oct 19

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[\[Abstract\]](#) [\[PDF Full-Text \(164 KB\)\]](#) **IEEE CNF**

---

**11 A novel salicide technology for thin film SOI MOSFETs using Ge pre-amorphization**

Hsiao, T.C.; Liu, P.; Woo, J.C.S.;

SOI Conference, 1996. Proceedings., 1996 IEEE International , 30 Sep-3 Oct 19

Page(s): 126 -127

[\[Abstract\]](#) [\[PDF Full-Text \(160 KB\)\]](#) **IEEE CNF**

---

**12 Performance analysis of a statistical test for presence of cyclostation in a noisy observation**

Rostaing, P.; Pitarque, T.; Thierry, E.;

Acoustics, Speech, and Signal Processing, 1996. ICASSP-96. Conference Procee  
1996 IEEE International Conference on , Volume: 5 , 7-10 May 1996

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[\[Abstract\]](#) [\[PDF Full-Text \(264 KB\)\]](#) **IEEE CNF**

---

**13 1.1 Ghz integer N phase lock loop with superior single event upset a total dose properties suitable for commercial space applications**

Lyons, G.;

SOI Conference, 1998. Proceedings., 1998 IEEE International , 5-8 Oct 1998

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---

**14 ELTRAN<sup>(R)</sup> by water-jet splitting in stress-controlled porous Si**

Sakaguchi, K.; Yanagita, K.; Kurisu, H.; Suzuki, H.; Ohmi, K.; Yonehara, T.;

SOI Conference, 1999. Proceedings. 1999 IEEE International , 1999

Page(s): 110 -111

[\[Abstract\]](#) [\[PDF Full-Text \(112 KB\)\]](#) **IEEE CNF**

---

**15 A dynamic body discharge technique for SOI circuit applications**

Kuang, J.B.; Saccamango, M.J.; Lu, P.F.; Chuang, C.T.; Assaderaghi, F.;

SOI Conference, 1999. Proceedings. 1999 IEEE International , 1999

Page(s): 77 -78



[\[Abstract\]](#) [\[PDF Full-Text \(104 KB\)\]](#) **IEEE CNF**

---

**16 Hysteresis effect in floating-body partially-depleted SOI CMOS domin circuits**

*Puri, R.; Chuang, C.T.;*

Low Power Electronics and Design, 1999. Proceedings. 1999 International Sym on , 1999

Page(s): 223 -228

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---

**17 Hysteresis in floating-body PD/SOI CMOS circuits**

*Pelella, M.M.; Chuang, C.T.; Tretz, C.; Curran, B.W.; Rosenfield, M.G.;*

VLSI Technology, Systems, and Applications, 1999. International Symposium o 1999

Page(s): 278 -281

[\[Abstract\]](#) [\[PDF Full-Text \(308 KB\)\]](#) **IEEE CNF**

---

**18 Converting a 64 b PowerPC processor from CMOS bulk to SOI techno**

*Allen, D.; Behrends, D.; Stanisic, B.;*

Design Automation Conference, 1999. Proceedings. 36th , 1999

Page(s): 892 -897

[\[Abstract\]](#) [\[PDF Full-Text \(568 KB\)\]](#) **IEEE CNF**

---

**19 Micromachined relay which utilizes single crystal silicon electrostatic actuator**

*Sakata, M.; Komura, Y.; Seki, T.; Kobayashi, K.; Sano, K.; Horiike, S.;*

Micro Electro Mechanical Systems, 1999. MEMS '99. Twelfth IEEE International Conference on , 17-21 Jan 1999

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[\[Abstract\]](#) [\[PDF Full-Text \(580 KB\)\]](#) **IEEE CNF**

---

**20 Design considerations and implementations of a high performance d register file**

*Joshi, R.V.; Hwang, W.;*

VLSI Design, 1999. Proceedings. Twelfth International Conference On , 7-10 Ja

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[\[Abstract\]](#) [\[PDF Full-Text \(984 KB\)\]](#) **IEEE CNF**

---

Joshi, R.V.; Hwang, W.; Wilson, S.; Shahidi, G.; Chuang, C.T.;  
VLSI Design, 2000. Thirteenth International Conference on , 2000  
Page(s): 44 -49

[\[Abstract\]](#) [\[PDF Full-Text \(728 KB\)\]](#) **IEEE CNF**

Liao, C.P.; Juang, K.C.; Huang, T.H.; Duh, D.S.; Yang, T.T.; Liu, M.N.;  
Semiconductor Manufacturing Technology Workshop, 2000 , 2000  
Page(s): 124 -132

[\[Abstract\]](#) [\[PDF Full-Text \(480 KB\)\]](#) **IEEE CNF**

Kuang, J.B.; Allen, D.H.; Chuang, C.T.;  
SOI Conference, 2000 IEEE International , 2000  
Page(s): 100 -101

[\[Abstract\]](#) [\[PDF Full-Text \(128 KB\)\]](#) **IEEE CNF**

Saccamango, M.J.; Kuang, J.B.; Hsu, L.L.; Ratanaphanyarat, S.;  
SOI Conference, 2000 IEEE International , 2000  
Page(s): 88 -89

[\[Abstract\]](#) [\[PDF Full-Text \(112 KB\)\]](#) **IEEE CNF**

Joshi, R.V.; Hwang, W.; Wilson, S.C.; Chuang, C.T.;  
Low Power Electronics and Design, 2000. ISLPED '00. Proceedings of the 2000  
International Symposium on , 2000  
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